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1 An image conversion algorithm from fish eye image to perspective i for human eyes

Ishii, C.; Sudo, Y.; Hashimoto, H.;

Advanced Intelligent Mechatronics, 2003. AIM 2003. Proceedings. 2003 IEEE/ International Conference on , Volume: 2 , 20-24 July 2003 Pages:1009 - 1014 vol.2

[Abstract] [PDF Full-Text (728 KB)] IEEE CNF

2 A method to extract spots from the image of the ELISA (enzyme-lin immunosorbent assay) spot assay

Chih-Yang Lin; Yu-Tai Ching; Wu-Hsieh, B.A.;

Engineering in Medicine and Biology Society, 2001. Proceedings of the 23rd A International Conference of the IEEE , Volume: 3 , 25-28 Oct. 2001 Pages: 2549 - 2552 vol. 3

[Abstract] [PDF Full-Text (756 KB)] IEEE CNF

3 Neural net based image retrieval by using color and location inform Inoue, M.; Mitsukura, Y.; Fukumi, M.; Akamatsu, N.;

Systems, Man, and Cybernetics, 2000 IEEE International Conference on, Volu 4 , 8-11 Oct. 2000

Pages: 2575 - 2579 vol.4

[Abstract] [PDF Full-Text (343 KB)]

4 "Control" diagnostic X-ray apparatus with a digital image visualizat system

Filatov, A.L.; Korjenevski, S.R.; Scherbinin, S.V.; High-Power Particle Beams, 1998. BEAMS '98. Proceedings of the 12th International Conference on , Volume: 1 , 7-12 June 1998

Pages:495 - 498 vol.1

[Abstract] [PDF Full-Text (276 KB)] IEEE CNF

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